

# **OptiMOS™-5 Power-Transistor**







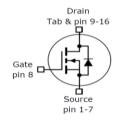
#### **Features**

- OptiMOS™ power MOSFET for automotive applications
- N-channel Enhancement mode Normal Level
- Extended qualification beyond AEC-Q101
- · Enhanced electrical testing
- Robust design
- MSL1 up to 260°C peak reflow
- 175°C operating temperature
- Green product (RoHS compliant)
- 100% Avalanche tested

Pro	auct	Sum	ımary
			,

$V_{\mathrm{DS}}$	80	V
R <sub>DS(on)</sub>	1.1	mΩ
I <sub>D</sub>	300	Α





Туре	Package	Marking		
IAUS300N08S5N011T	PG-HDSOP-16-2	5N08011		

#### **Maximum ratings,** at $T_i$ =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit	
Continuous drain current	I <sub>D</sub>	V <sub>GS</sub> =10 V, Chip limitation <sup>1,2)</sup>	400	А	
		V <sub>GS</sub> =10V, DC current <sup>3)</sup>	300		
		$T_{\rm a}$ =85 °C, $V_{\rm GS}$ =10 V, $R_{\rm thJA}$ on 2s2p <sup>2,4)</sup>	123		
Pulsed drain current <sup>2)</sup>	I <sub>D,pulse</sub>	$T_{\rm C}$ =25 °C, $t_{\rm p}$ = 100 μs	1450		
Avalanche energy, single pulse <sup>2)</sup>	E <sub>AS</sub>	I <sub>D</sub> =150 A	817	mJ	
Avalanche current, single pulse	IAS	-	300	А	
Gate source voltage	$V_{GS}$	-	±20	V	
Power dissipation	$P_{\text{tot}}$	T <sub>C</sub> =25 °C	375	W	
Operating and storage temperature	$T_{\rm j},T_{\rm stg}$	-	-55 +175	°C	
IEC climatic category; DIN IEC 68-1	-	-	55/175/56		



Parameter	Symbol Conditions		Values			Unit
			min.	typ.	max.	1
Thermal characteristics <sup>2)</sup>						
	$R_{thJC}$	Тор	-	-	0.4	K/W
Thermal resistance, junction - case		Bottom (Pin 1-7)	-	9	-	
		Bottom (Pin 9-16)	-	3	-	
Thermal resistance, junction -	$R_{thJA}$	Тор	-	2.8	-	
ambient <sup>4)</sup>		Bottom (through PCB)	-	40	-	

# **Electrical characteristics,** at $T_j$ =25 °C, unless otherwise specified

#### Static characteristics

Drain-source breakdown voltage	V <sub>(BR)DSS</sub>	$V_{\rm GS}$ =0 V, $I_{\rm D}$ =1 mA	80	1	-	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{\rm DS} = V_{\rm GS}, I_{\rm D} = 275  \mu {\rm A}$	2.2	3	3.8	
Zero gate voltage drain current	I <sub>DSS</sub>	$V_{\rm DS} = 80 \text{ V}, V_{\rm GS} = 0 \text{ V}, $ $T_{\rm j} = 25 \text{ °C}$	ı	0.1	1	μΑ
		$V_{\rm DS}$ =50 V, $V_{\rm GS}$ =0 V, $T_{\rm j}$ =85 °C <sup>2)</sup>	-	1	20	
Gate-source leakage current	I <sub>GSS</sub>	V <sub>GS</sub> =20 V, V <sub>DS</sub> =0 V	-	-	100	nA
Drain-source on-state resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =6 V, I <sub>D</sub> =75 A	-	1.4	1.8	mΩ
		V <sub>GS</sub> =10 V, I <sub>D</sub> =100 A		1.0	1.1	
Gate resistance <sup>2)</sup>	$R_{G}$	-	-	1.5	-	Ω



Parameter	Symbol Conditions		Values			Unit
			min.	typ.	max.	
Dynamic characteristics <sup>2)</sup>						
Input capacitance	Ciss		-	12500	16250	pF
Output capacitance	Coss	V <sub>GS</sub> =0 V, V <sub>DS</sub> =40 V, f=1 MHz	-	2000	2600	1
Reverse transfer capacitance	C <sub>rss</sub>		-	86	130	
Turn-on delay time	t <sub>d(on)</sub>		-	31	-	ns
Rise time	t <sub>r</sub>	V <sub>DD</sub> =40 V, V <sub>GS</sub> =10 V,	-	19	-	1
Turn-off delay time	$t_{d(off)}$	$I_{\rm D}$ =100 A, $R_{\rm G}$ =3.5 Ω	-	69	-	
Fall time	$t_{f}$		-	55	-	1
Gate Charge Characteristics <sup>2)</sup> Gate to source charge	Q <sub>gs</sub>	<u> </u>		56	73	nC
Gate to drain charge	Q <sub>gd</sub>	$V_{\rm DD}$ =40 V, $I_{\rm D}$ =100 A, $V_{\rm GS}$ =0 to 10 V	<u> </u>	37	56	-
Gate charge total	Q <sub>g</sub>		-	178	231	<u> </u>
Gate plateau voltage	V <sub>plateau</sub>		-	4.5	-	V
Reverse Diode						
Diode continous forward current <sup>2)</sup>	Is	T <sub>C</sub> =25 °C	-	-	300	А
Diode pulse current <sup>2)</sup>	I <sub>S,pulse</sub>	$T_{\rm C}$ =25 °C, $t_{\rm p}$ = 100 μs	-	-	2300	
Diode forward voltage	V <sub>SD</sub>	V <sub>GS</sub> =0 V, I <sub>F</sub> =100 A, T <sub>j</sub> =25 °C	-	0.9	1.2	V
Reverse recovery time <sup>2)</sup>	t <sub>rr</sub>	V <sub>R</sub> =40 V, I <sub>F</sub> =50A,	-	86	-	ns
Reverse recovery charge <sup>2)</sup>	Q <sub>rr</sub>	d <i>i<sub>F</sub></i> /d <i>t</i> =100 A/µs	_	177	_	nC

<sup>&</sup>lt;sup>1)</sup> Practically the current is limited by the overall system design including the customer-specific PCB.

<sup>&</sup>lt;sup>2)</sup> The parameter is not subject to production testing – specified by design.

<sup>&</sup>lt;sup>3)</sup> Current is limited by the bondwires.

 $<sup>^{4)}</sup>$  Device on a four-layer 2s2p FR4 PCB with topside cooling. Thermal insulation material is 100  $\mu$ m thick and has a conductivity of 0.7 W/mK. Top surface of heat sink is fixed at ambient temperature. Bottom surface of PCB is left at free convection. Values may vary depending on the customer-specific design.



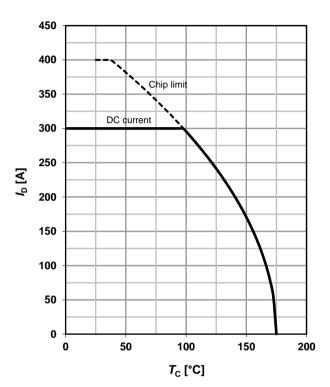
#### 1 Power dissipation

$$P_{\text{tot}} = f(T_{\text{C}}); V_{\text{GS}} \ge 6 \text{ V}$$

# 300 300 100 100 0 0 0 0 100 150 200 T<sub>C</sub> [°C]

#### 2 Drain current

$$I_D = f(T_C); V_{GS} \ge 6 \text{ V}$$



# 3 Safe operating area

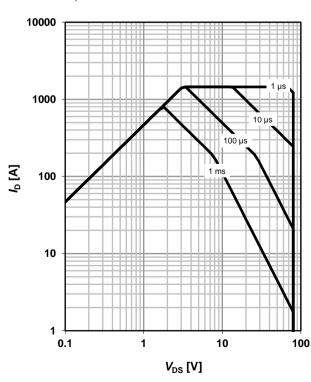
$$I_D = f(V_{DS}); T_C = 25 \text{ °C}; D = 0$$

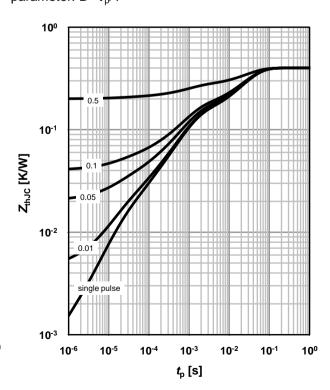
parameter:  $t_p$ 

#### 4 Max. transient thermal impedance

$$Z_{\text{thJC}} = f(t_{p})$$

parameter:  $D=t_p/T$ 



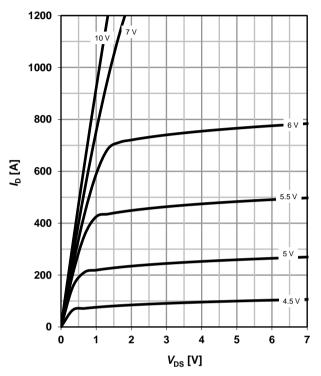




# 5 Typ. output characteristics

 $I_D = f(V_{DS}); T_i = 25 \text{ °C}$ 

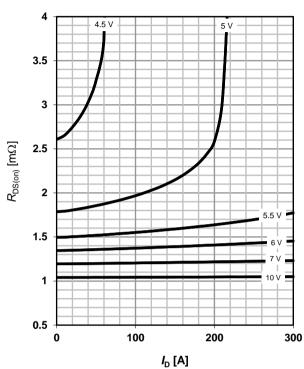
parameter: V<sub>GS</sub>



#### 6 Typ. drain-source on-state resistance

 $R_{DS(on)} = f(I_D); T_j = 25 \text{ °C}$ 

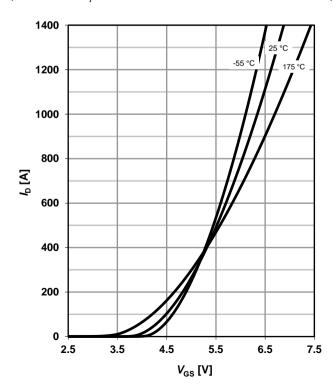
parameter:  $V_{\rm GS}$ 



# 7 Typ. transfer characteristics

 $I_D = f(V_{GS}); V_{DS} = 6V$ 

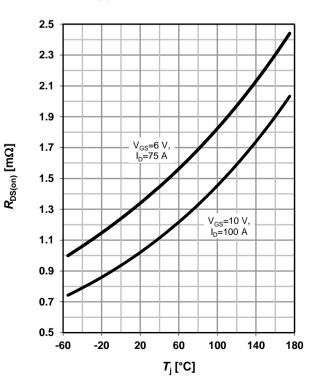
parameter:  $T_{\rm j}$ 



# 8 Typ. drain-source on-state resistance

 $R_{DS(on)} = f(T_j)$ 

parameter:  $I_D$ ,  $V_{GS}$ 





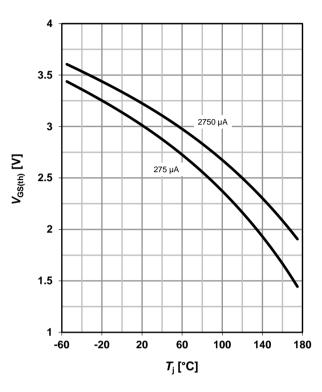
# 9 Typ. gate threshold voltage

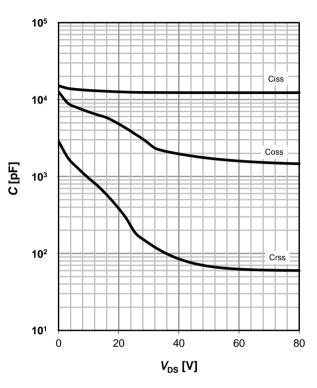
 $V_{GS(th)} = f(T_i); V_{GS} = V_{DS}$ 

parameter: I<sub>D</sub>

# 10 Typ. capacitances

 $C = f(V_{DS}); V_{GS} = 0 V; f = 1 MHz$ 





# 11 Typical forward diode characteristics

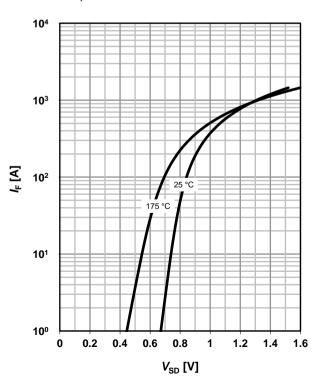
 $I_F = f(V_{SD})$ 

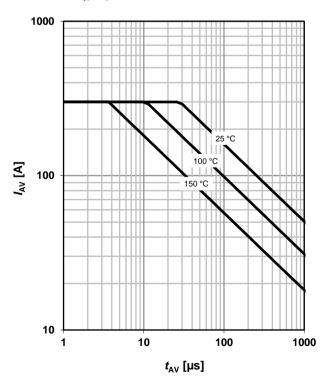
parameter:  $T_{\rm j}$ 

# 12 Typ. avalanche characteristics

 $I_{AS} = f(t_{AV})$ 

parameter:  $T_{j(start)}$ 







# 13 Typical avalanche energy

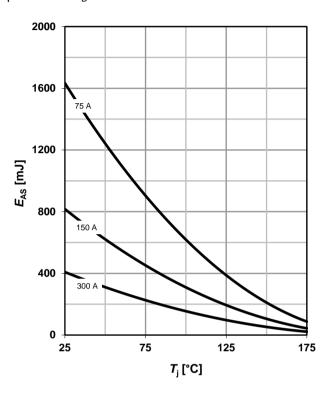
 $E_{AS} = f(T_i)$ 

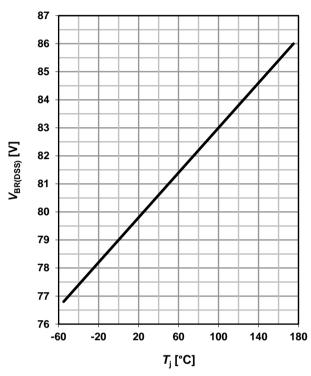
parameter: I<sub>D</sub>

#### 14 Drain-source breakdown voltage

$$V_{BR(DSS)} = f(T_j); I_{D_{typ}} = 1 \text{ mA}$$

16 Gate charge waveforms

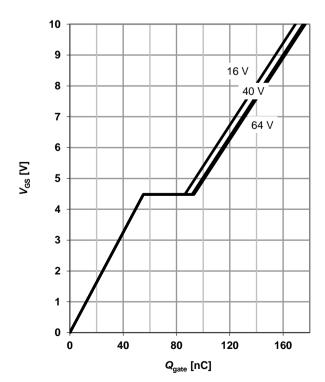


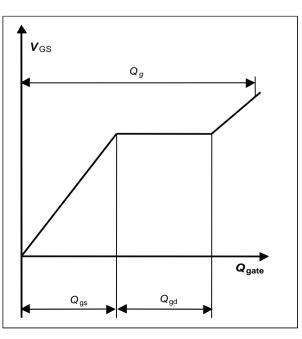


# 15 Typ. gate charge

 $V_{GS} = f(Q_{gate}); I_D = 100 A pulsed$ 

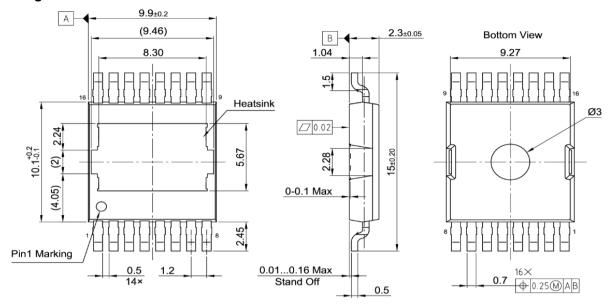
parameter: V<sub>DD</sub>



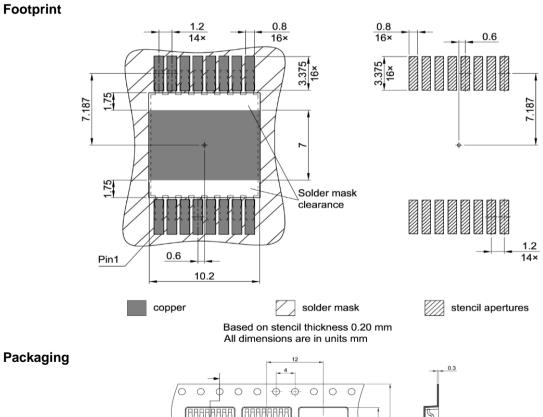




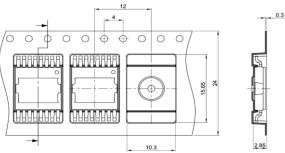
#### **Package Outline**



All metal surfaces tin plated except area of cut and heatsink
All dimensions are in units mm
The drawing is in compliance with ISO 128-30, Projection Method 1 [









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**Revision History** 

Version	Date	Changes		
Version 1.0	01.10.2020	Final Datasheet		